Electronic Supplementary Information for

# Mechanical exfoliation and electrical characterization of one-dimensional $Nb_2Se_9$ atomic crystal

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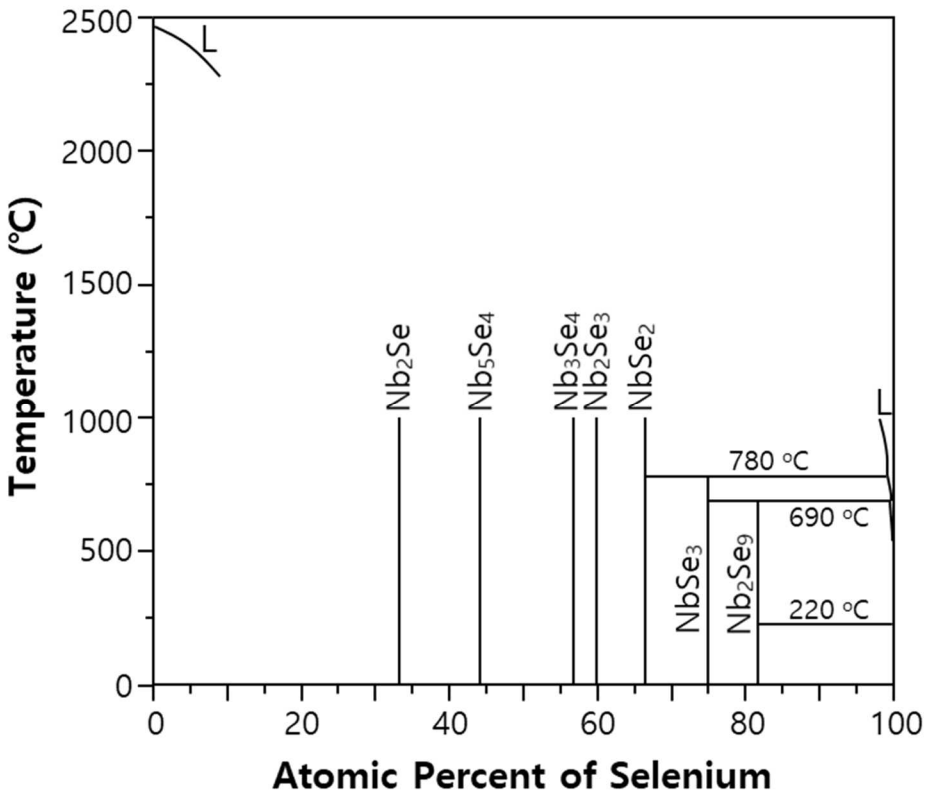


**Figure S1.** Phase diagram of Nb-Se binary system.

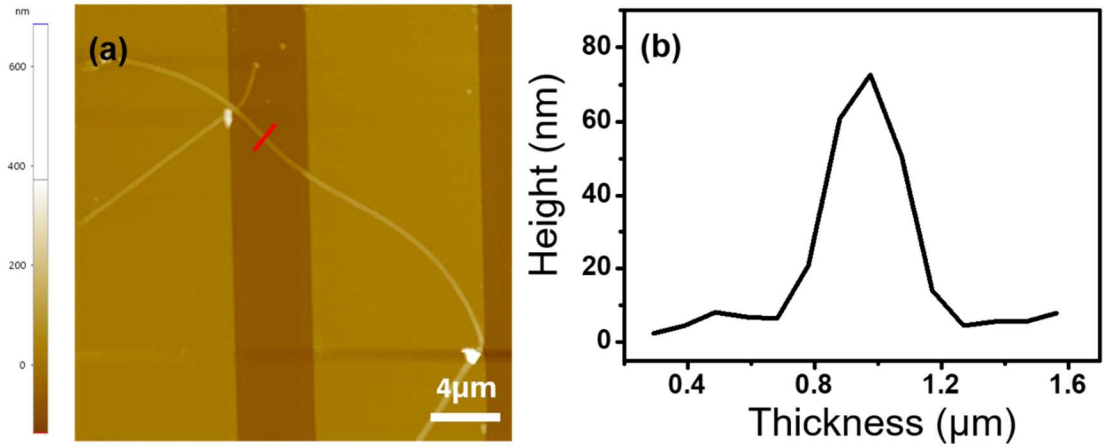


**Figure S2. (a)** AFM image of the $Nb_2Se_9$ FET. (b) Line profile of the corresponding $Nb_2Se_9$ flake, as marked in (a)